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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China



AUTOMOTIVE MOSFET

PD - 94653B

IRF3205Z

IRF3205ZS

IRF3205ZL

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to T_{jmax}

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.

HEXFET® Power MOSFET

	$V_{DSS} = 55V$
	$R_{DS(on)} = 6.5m\Omega$
	$I_D = 75A$
	TO-220AB IRF3205Z
	D ² Pak IRF3205ZS
	TO-262 IRF3205ZL

Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	110	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	78	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	75	
I_{DM}	Pulsed Drain Current ①	440	
$P_D @ T_C = 25^\circ C$	Power Dissipation	170	W
	Linear Derating Factor	1.1	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ②	180	mJ
E_{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ⑥	250	
I_{AR}	Avalanche Current ①	See Fig.12a, 12b, 15, 16	A
E_{AR}	Repetitive Avalanche Energy ⑤		mJ
T_J	Operating Junction and	-55 to + 175	$^\circ C$
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw ⑦	10 lbf \cdot in (1.1N \cdot m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
R_{0JC}	Junction-to-Case	—	0.90	$^\circ C/W$
R_{0CS}	Case-to-Sink, Flat Greased Surface ⑧	0.50	—	
R_{0JA}	Junction-to-Ambient ⑨	—	62	
R_{0JA}	Junction-to-Ambient (PCB Mount) ⑩	—	40	

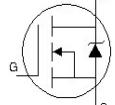
IRF3205ZS/L

International
Rectifier

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.051	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	4.9	6.5	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}$, $I_D = 66\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	71	—	—	S	$V_{\text{DS}} = 25\text{V}$, $I_D = 66\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{\text{DS}} = 55\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 55\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{\text{GS}} = -20\text{V}$
Q_g	Total Gate Charge	—	76	110		$I_D = 66\text{A}$
Q_{gs}	Gate-to-Source Charge	—	21	—		$V_{\text{DS}} = 44\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	30	—		$V_{\text{GS}} = 10\text{V}$ ③
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	18	—		$V_{\text{DD}} = 28\text{V}$
t_r	Rise Time	—	95	—		$I_D = 66\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	45	—		$R_G = 6.8 \Omega$
t_f	Fall Time	—	67	—		$V_{\text{GS}} = 10\text{V}$ ③
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	3450	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	550	—		$V_{\text{DS}} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	310	—		$f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	1940	—		$V_{\text{GS}} = 0\text{V}$, $V_{\text{DS}} = 1.0\text{V}$, $f = 1.0\text{MHz}$
C_{oss} eff.	Output Capacitance	—	430	—		$V_{\text{GS}} = 0\text{V}$, $V_{\text{DS}} = 44\text{V}$, $f = 1.0\text{MHz}$
C_{oss} eff.	Effective Output Capacitance	—	640	—		$V_{\text{GS}} = 0\text{V}$, $V_{\text{DS}} = 0\text{V}$ to 44V ④

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	75	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	440		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$, $I_S = 66\text{A}$, $V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	28	42	ns	$T_J = 25^\circ\text{C}$, $I_F = 66\text{A}$, $V_{\text{DD}} = 25\text{V}$
Q_{rr}	Reverse Recovery Charge	—	25	38	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $LS+LD$)				

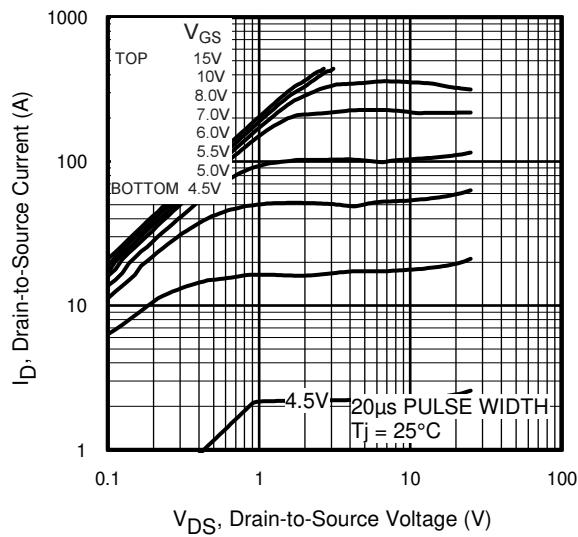


Fig 1. Typical Output Characteristics

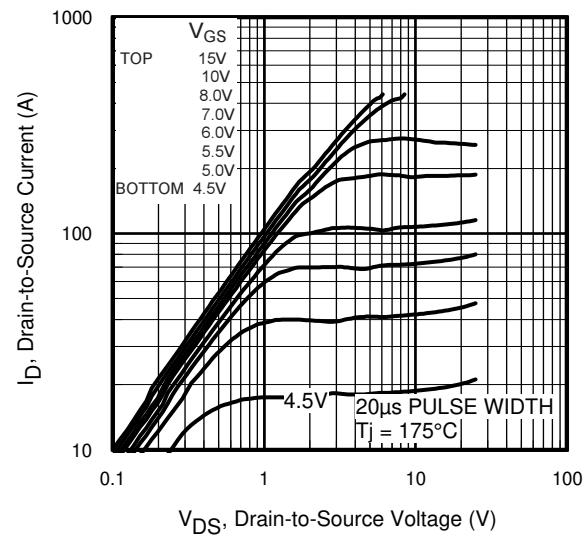


Fig 2. Typical Output Characteristics

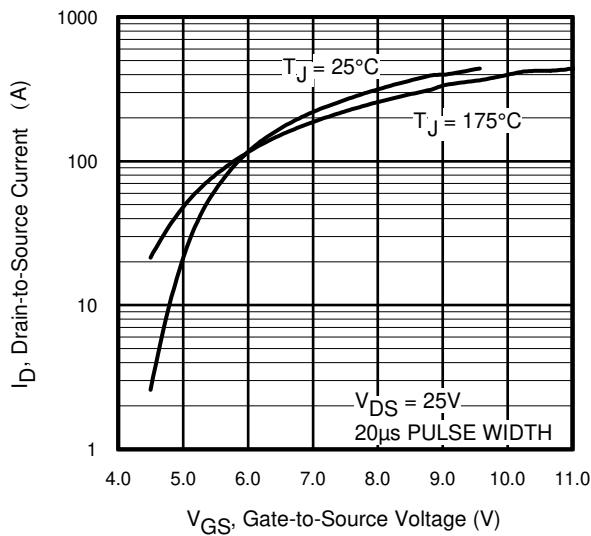


Fig 3. Typical Transfer Characteristics

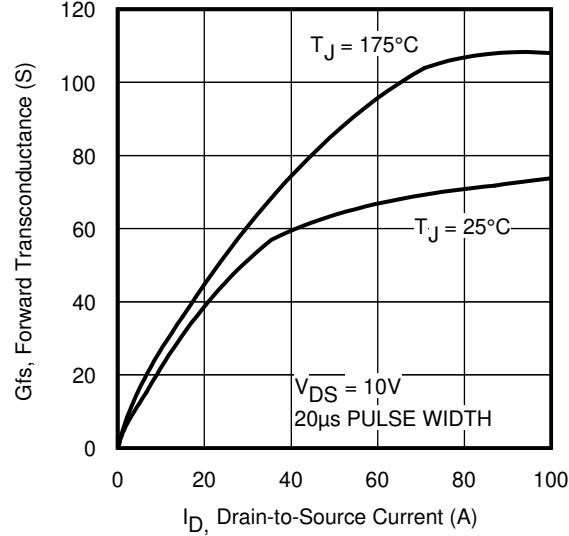


Fig 4. Typical Forward Transconductance Vs. Drain Current

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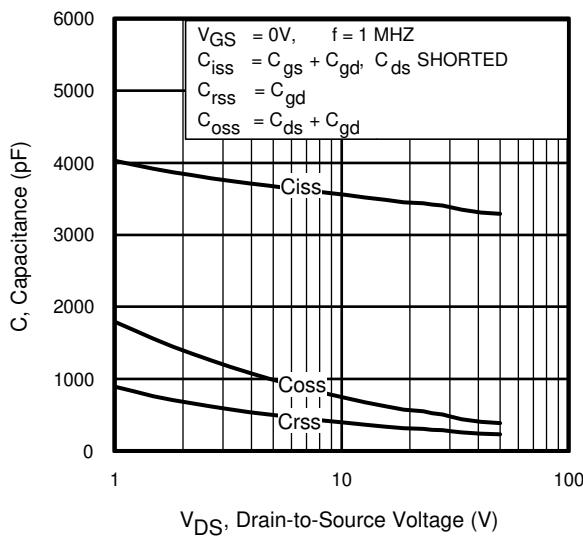


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

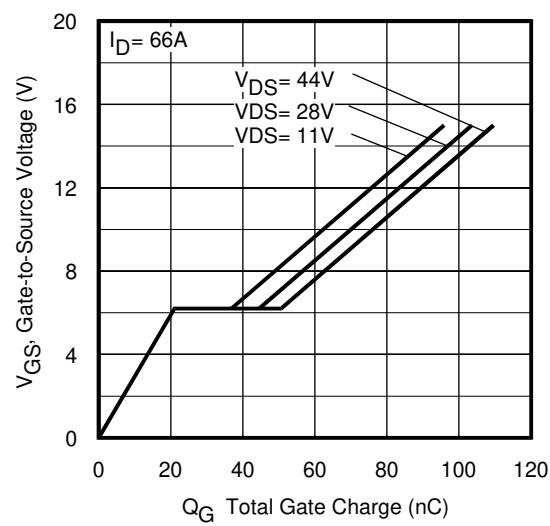


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

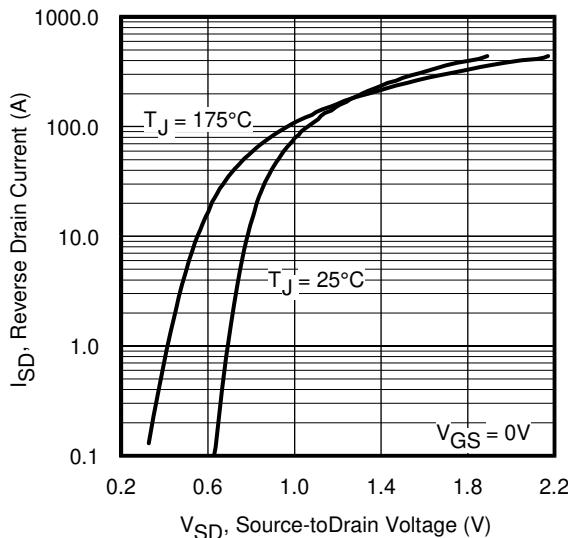


Fig 7. Typical Source-Drain Diode
Forward Voltage

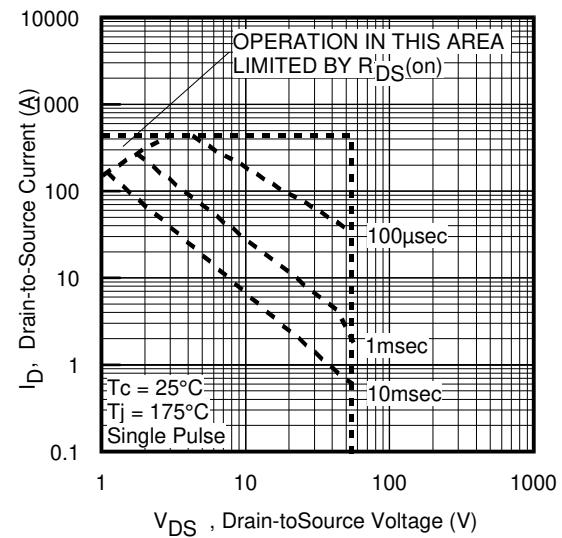


Fig 8. Maximum Safe Operating Area

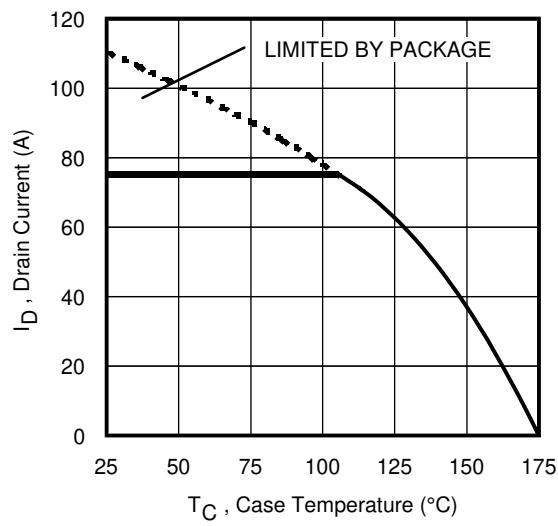


Fig 9. Maximum Drain Current Vs.
Case Temperature

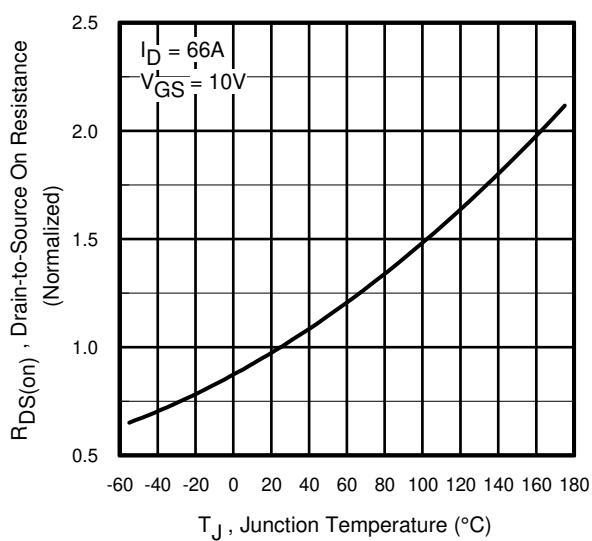


Fig 10. Normalized On-Resistance
Vs. Temperature

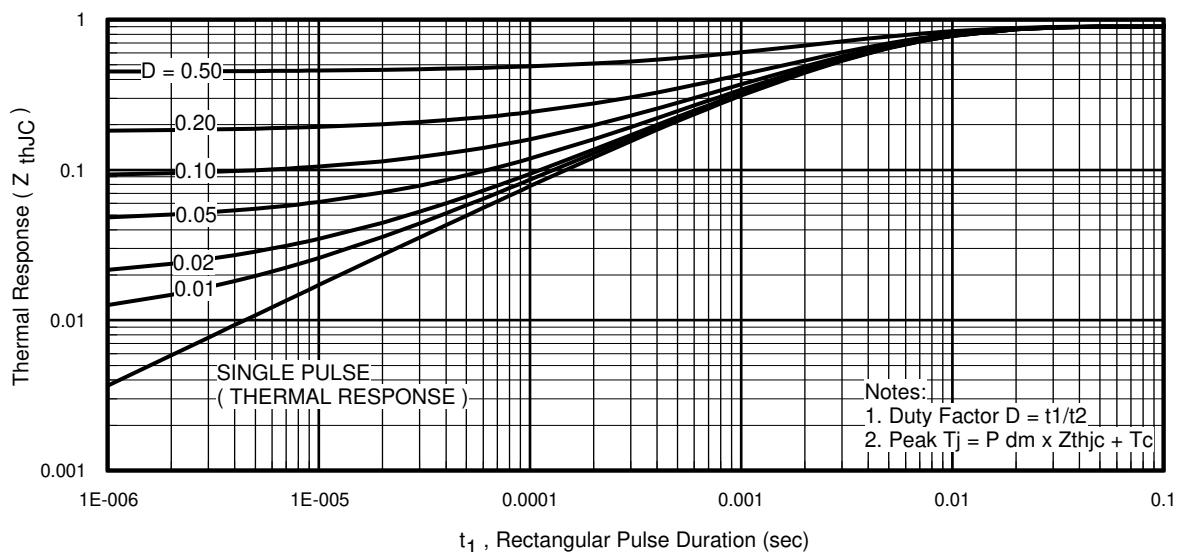
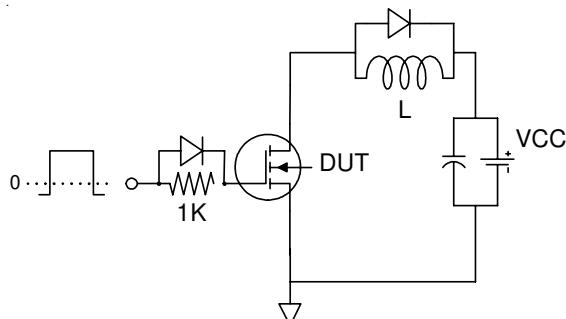
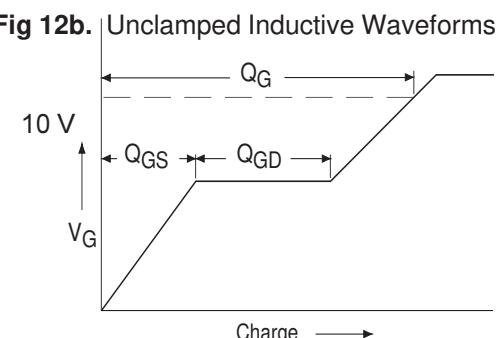
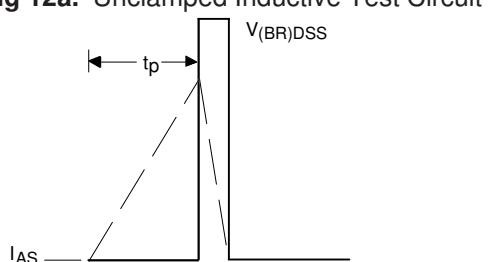
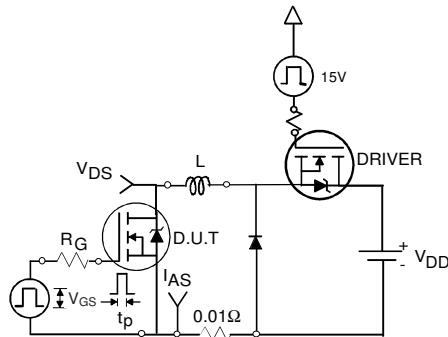


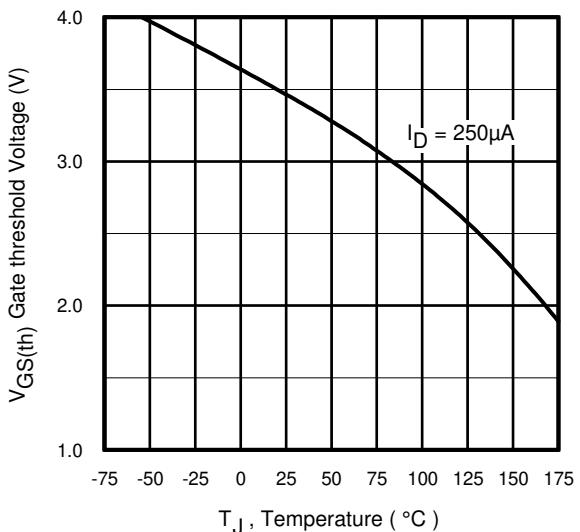
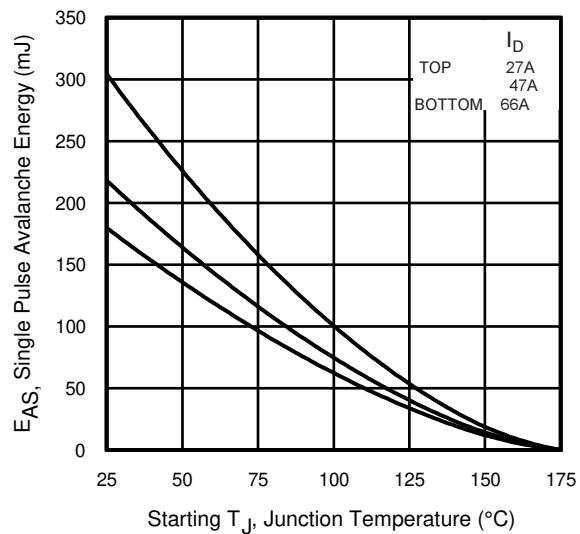
Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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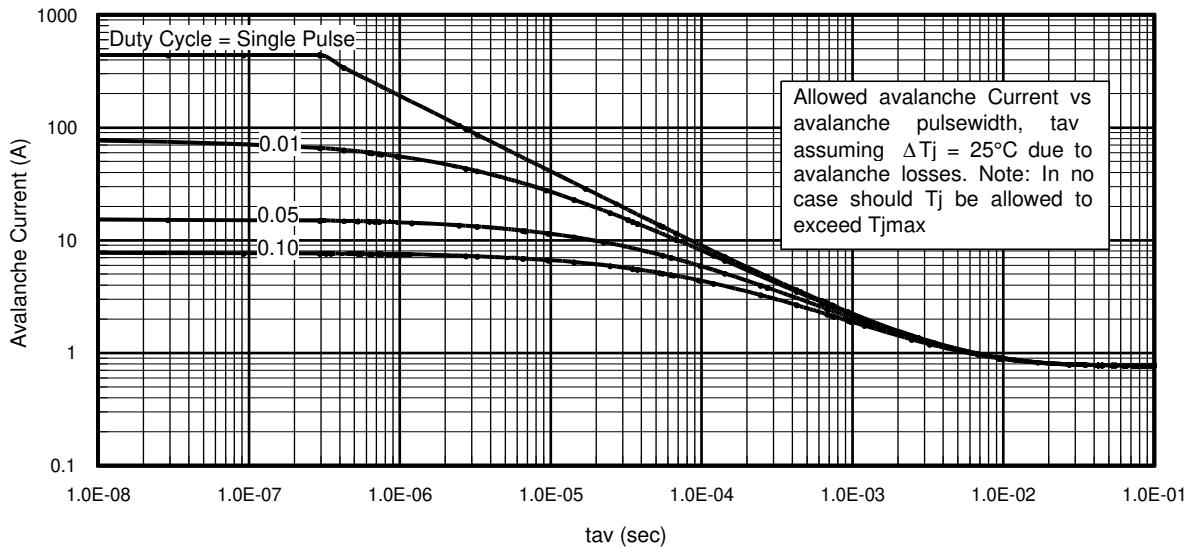


Fig 15. Typical Avalanche Current Vs.Pulsewidth

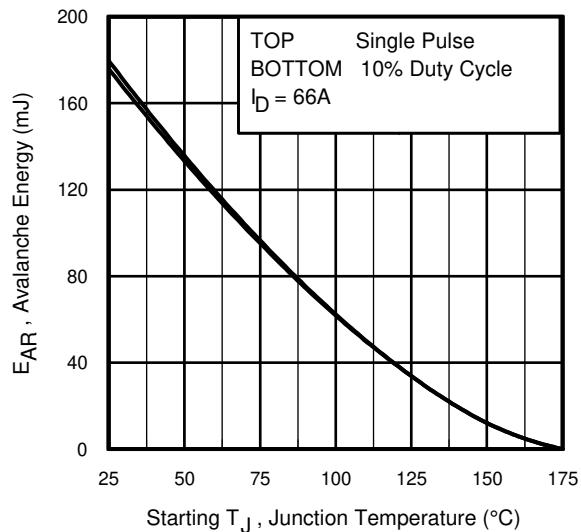


Fig 16. Maximum Avalanche Energy
Vs. Temperature

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**Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.irf.com)**

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of $T_{j\max}$. This is validated for every part type.
 2. Safe operation in Avalanche is allowed as long as $T_{j\max}$ is not exceeded.
 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
 4. $P_{D(\text{ave})}$ = Average power dissipation per single avalanche pulse.
 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
 6. I_{av} = Allowable avalanche current.
 7. ΔT = Allowable rise in junction temperature, not to exceed $T_{j\max}$ (assumed as 25°C in Figure 15, 16).
- t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$P_{D(\text{ave})} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(\text{ave})} \cdot t_{av}$$

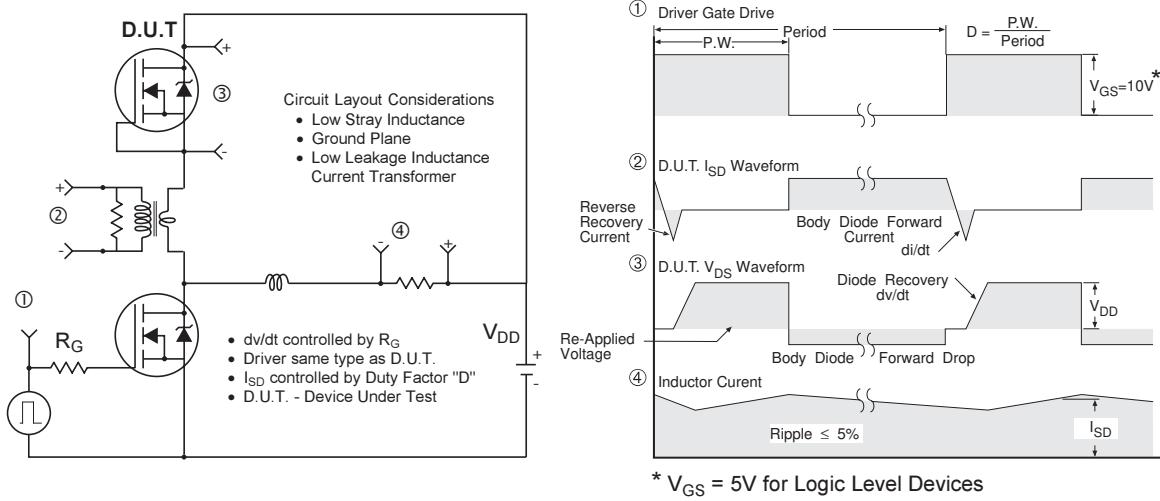


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

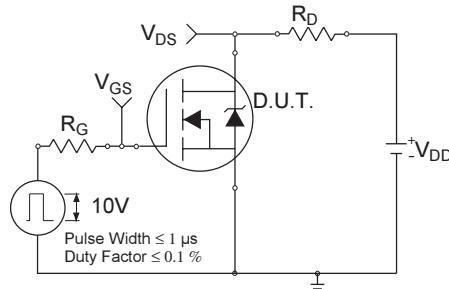


Fig 18a. Switching Time Test Circuit

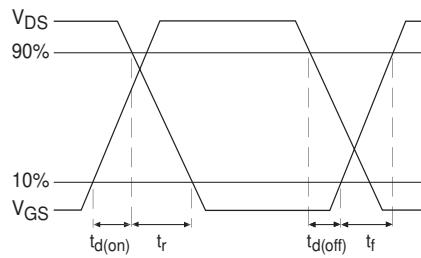
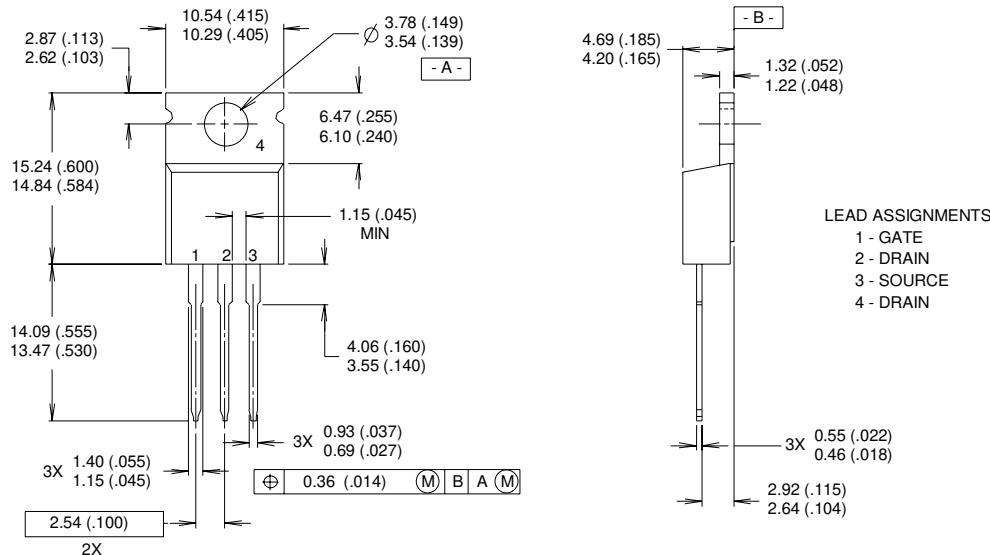


Fig 18b. Switching Time Waveforms

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



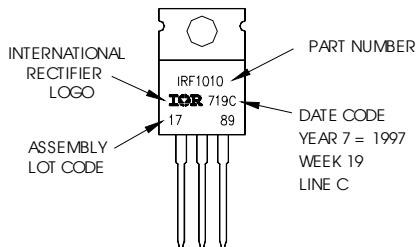
NOTES:

- 1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
- 2 CONTROLLING DIMENSION : INCH

- 3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

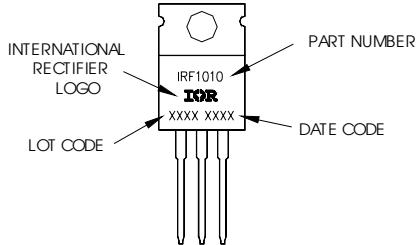
TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"



For GB Production

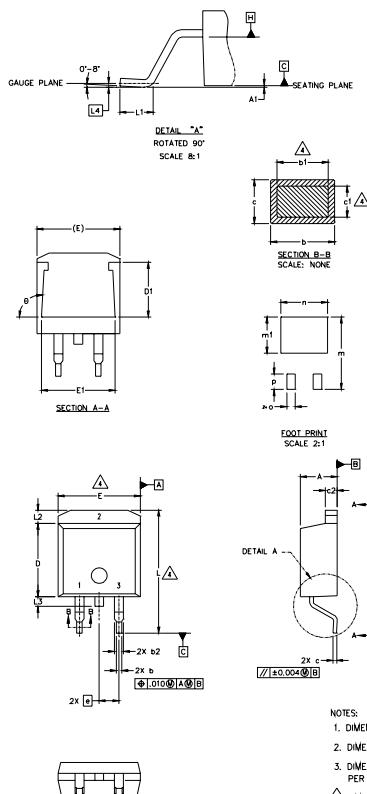
EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"



IRF3205ZS/L

D²Pak Package Outline

Dimensions are shown in millimeters (inches)



SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	0.51	0.99	.020	.039	4	
b	0.51	0.89	.020	.035		
b1	0.51	0.89				
b2	1.14	1.40	.045	.055		
c	0.43	0.63	.017	.025		
c1	0.38	0.74	.015	.029	4	
c2	1.14	1.40	.045	.055		
D	8.51	9.65	.335	.380	3	
D1	5.33		.210			
E	9.65	10.67	.380	.420	3	
E1	6.22		.245			
e	2.54	BSC	.100	BSC		
L	14.61	15.88	.575	.625		
L1	1.78	2.79	.070	.110		
L2		1.65		.065		
L3	1.27	1.78	.050	.070		
L4	0.25	BSC	.010	BSC		
m	17.78		.700			
m1	8.89		.350			
n	11.43		.450			
o	2.08		.082			
p	3.81		.150			
θ	90°	93°	90°	93°		

LEAD ASSIGNMENTS

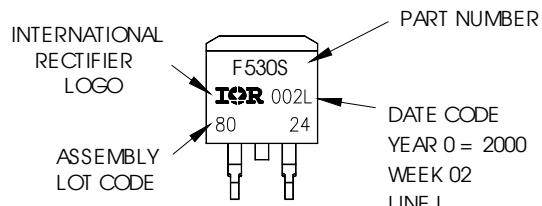
HEXFET	IGBTs, CoPACK	DIODES
1.- GATE	1.- GATE	1.- ANODE *
2.- DRAIN	2.- COLLECTOR	2.- CATHODE
3.- SOURCE	3.- Emitter	3.- ANODE

* PART DEPENDENT.

- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES]
 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
 4. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
 5. CONTROLLING DIMENSION: INCH.

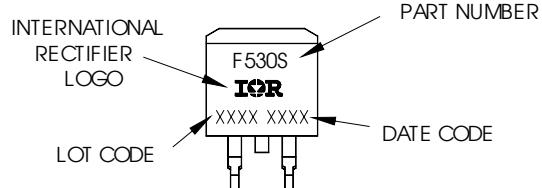
D²Pak Part Marking Information

EXAMPLE: THIS IS AN IRF530S WITH
LOT CODE 8024
ASSEMBLED ON WW 02, 2000
IN THE ASSEMBLY LINE "L"



For GB Production

EXAMPLE: THIS IS AN IRF530S WITH
LOT CODE 8024
ASSEMBLED ON WW 02, 2000
IN THE ASSEMBLY LINE "L"

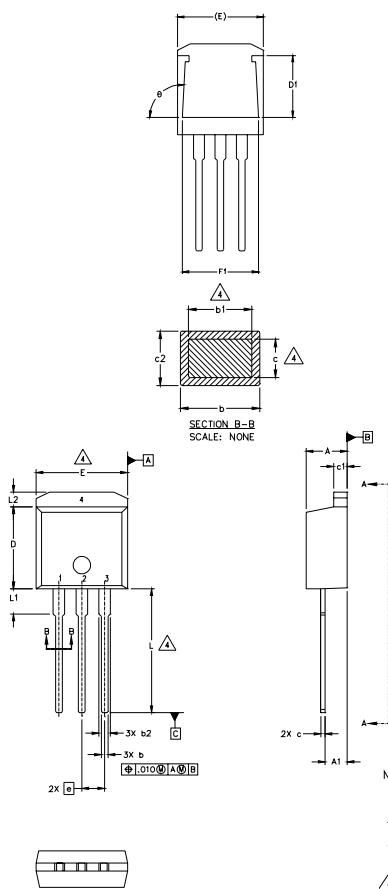


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IRF3205ZS/L

TO-262 Package Outline

Dimensions are shown in millimeters (inches)



S Y M B O L	DIMENSIONS				N O T E S	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	2.03	2.92	.080	.115		
b	0.51	0.99	.020	.039	4	
b1	0.51	0.89	.020	.035	4	
b2	1.14	1.40	.045	.055		
c	0.38	0.63	.015	.025		
c1	1.14	1.40	.045	.055		
c2	0.43	.063	.017	.029		
D	8.51	9.65	.335	.380	3	
D1	5.33		.210			
E	9.65	10.67	.380	.420	3	
E1	6.22		.245			
e	2.54	BSC	.100	BSC		
L	13.46	14.09	.530	.555		
L1	3.56	3.71	.140	.146		
L2		1.65		.065		

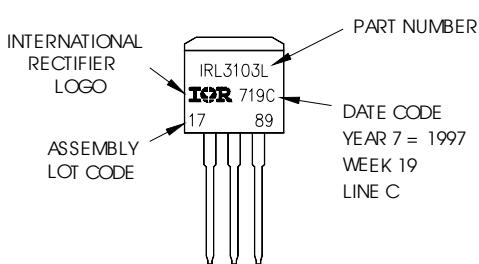
LEAD ASSIGNMENTS

HEXFET	IGBT
1.- GATE	1- GATE
2.- DRAIN	2- COLLECTOR
3.- SOURCE	
4.- DRAIN	

- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
 4. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
 5. CONTROLLING DIMENSION: INCH.

TO-262 Part Marking Information

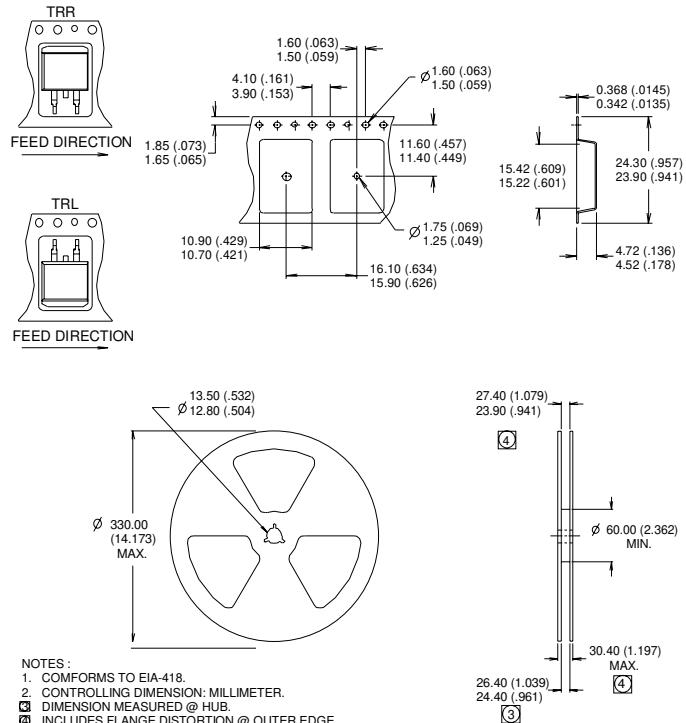
EXAMPLE: THIS IS AN IRL3103L
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"



IRF3205ZS/L

International
IR Rectifier

D²Pak Tape & Reel Information



Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by $T_{J\max}$, starting $T_J = 25^\circ\text{C}$, $L = 0.08\text{mH}$ $R_G = 25\Omega$, $I_{AS} = 66\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above this value.
- ③ Pulse width $\leq 1.0\text{ms}$; duty cycle $\leq 2\%$.
- ④ $C_{oss\ eff}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑤ Limited by $T_{J\max}$, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population. 100% tested to this value in production.
- ⑦ This is only applied to TO-220AB package.
- ⑧ This is applied to D²Pak, when mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

TO-220AB package is not recommended for Surface Mount Application.

Data and specifications subject to change without notice.
This product has been designed and qualified for the Automotive [Q101]market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
TAC Fax: (310) 252-7903
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